

July–August 1999  
Volume 104, Number 4

ISSN 1044-677X



***Journal of Research of the***

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# **National Institute of Standards and Technology**



United States Department of Commerce  
Technology Administration  
National Institute of Standards and Technology

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- High Performance Systems and Services
- Distributed Computing and Information Services
- Software Diagnostics and Conformance Testing
- Statistical Engineering

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<sup>1</sup>At Boulder, CO 80303.

<sup>2</sup>Some elements at Boulder, CO.

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**ISSN 1044-677X**

**Coden: JRITEF**

**Library of Congress Catalog Card No.: 89-656121**

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United States Government Printing Office, Washington: 1999

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*Available online*  
<http://www.nist.gov/jres>

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